



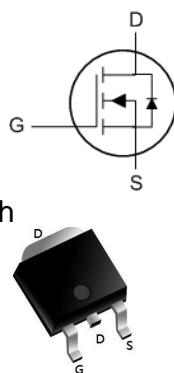
## N-Ch 60V Fast Switching MOSFETs

### Description

The 30N06 is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The 30N06 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

100% EAS Guaranteed  
Green Device Available  
Super Low Gate Charge  
Excellent CdV/dt effect decline  
Advanced high cell density Trench technology

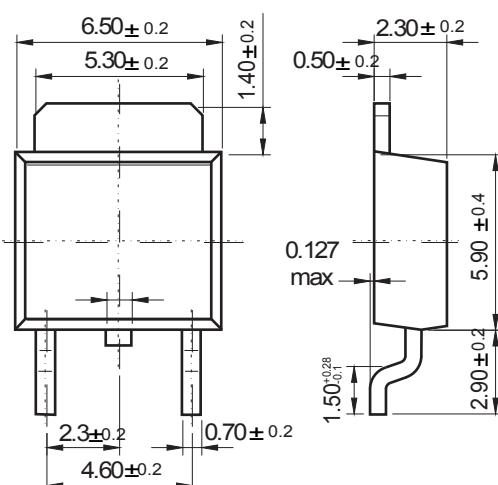


### Product Summary

BVDSS	RDS(on)	ID
60V	23mΩ	30 A

### TO-252

Unit: mm



Dimensions in inches and (millimeters)

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		60	V
$V_{GSS}$	Gate-Source Voltage		$\pm 30$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ\text{C}$	30	A
		$T_C = 100^\circ\text{C}$	13	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		100	A
EAS	Single Pulsed Avalanche Energy <sup>note2</sup>		39	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ\text{C}$	41.7	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		50	$^\circ\text{C}/\text{W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +175	$^\circ\text{C}$

# 30N06

## Electrical Characteristics ( $T_J = 25^\circ\text{C}$ , unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	60	-	-	V
Gate-Body Leakage Current	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$	-	-	$\pm 100$	nA
Zero Gate Voltage Drain Current $T_J=25^\circ\text{C}$ $T_J=100^\circ\text{C}$	$I_{\text{DSS}}$	$V_{\text{DS}} = 60\text{V}, V_{\text{GS}} = 0\text{V}$	-	-	1	$\mu\text{A}$
			-	-	100	
Gate-Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.2	1.7	2.5	V
Drain-Source on-Resistance <sup>4</sup>	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 10\text{A}$	-	23	32	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 5\text{A}$	-	31.5	40	
Forward Transconductance <sup>4</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 5\text{V}, I_D = 10\text{A}$	-	15.5	-	S
<b>Dynamic Characteristics<sup>5</sup></b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 30\text{V}, V_{\text{GS}} = 0\text{V}, f = 1\text{MHz}$	-	1355	-	$\text{pF}$
Output Capacitance	$C_{\text{oss}}$		-	60	-	
Reverse Transfer Capacitance	$C_{\text{rss}}$		-	49	-	
Gate Resistance	$R_G$	$f = 1\text{MHz}$	-	1.2	-	$\Omega$
<b>Switching Characteristics<sup>5</sup></b>						
Total Gate Charge	$Q_g$	$V_{\text{GS}} = 10\text{V}, V_{\text{DD}} = 30\text{V}, I_D = 10\text{A}$	-	22	-	$\text{nC}$
Gate-Source Charge	$Q_{\text{gs}}$		-	4.2	-	
Gate-Drain Charge	$Q_{\text{gd}}$		-	6.9	-	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, V_{\text{DD}} = 30\text{V}, R_G = 3\Omega, I_D = 10\text{A}$	-	6.4	-	$\text{ns}$
Rise Time	$t_r$		-	15.3	-	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		-	25	-	
Fall Time	$t_f$		-	7.6	-	
Body Diode Reverse Recovery Time	$t_{\text{rr}}$	$I_F = 10\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$	-	26	-	$\text{ns}$
Body Diode Reverse Recovery Charge	$Q_{\text{rr}}$		-	45	-	$\text{nC}$
<b>Drain-Source Body Diode Characteristics</b>						
Diode Forward Voltage <sup>4</sup>	$V_{\text{SD}}$	$I_S = 10\text{A}, V_{\text{GS}} = 0\text{V}$	-	-	1.2	V
Continuous Source Current	$T_C = 25^\circ\text{C}$	$I_S$	-	-	30	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$
2. The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}=25\text{V}, V_{\text{GS}}=10\text{V}, L=0.4\text{mH}, I_{\text{AS}}=14\text{A}$
3. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$ .
5. This value is guaranteed by design hence it is not included in the production test.

## RATING AND CHARACTERISTIC CURVES (30N06)

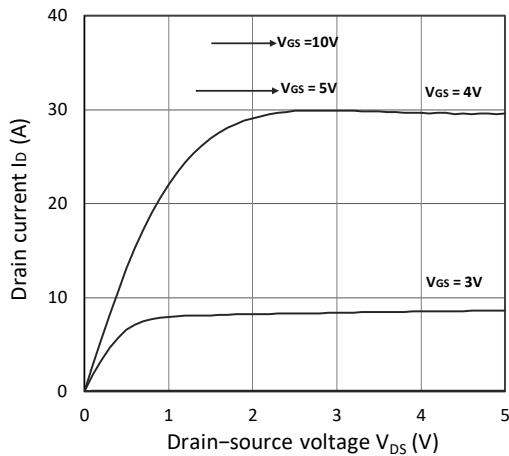


Figure 1. Output Characteristics

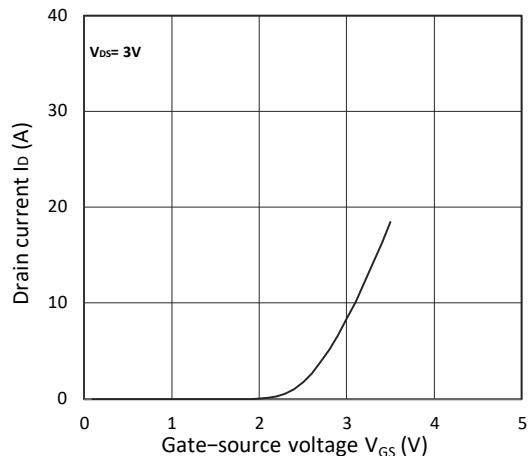


Figure 2. Transfer Characteristics

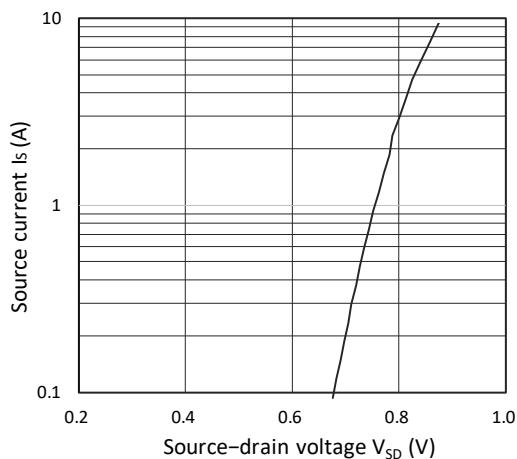


Figure 3. Forward Characteristics of Reverse

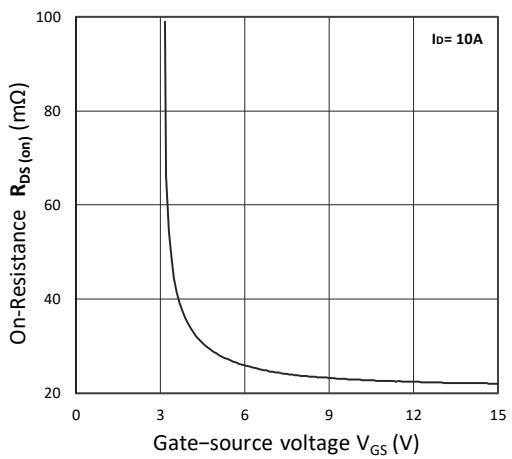


Figure 4.  $R_{DS(on)}$  vs.  $V_{GS}$

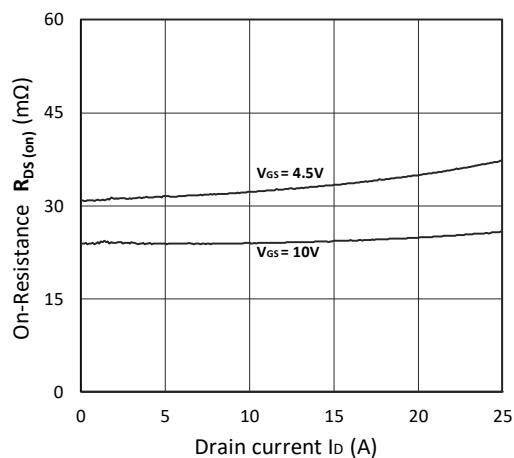


Figure 5.  $R_{DS(on)}$  vs.  $I_D$

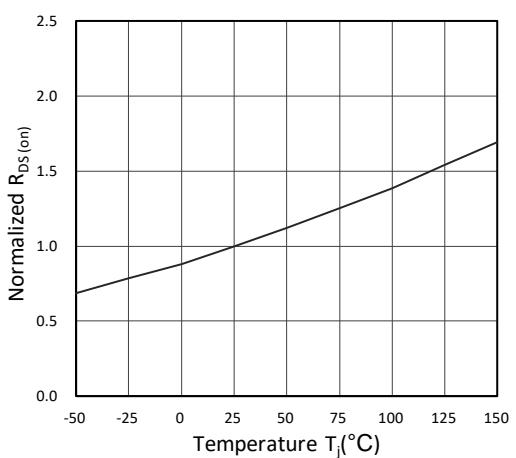


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

## RATING AND CHARACTERISTIC CURVES (30N06)

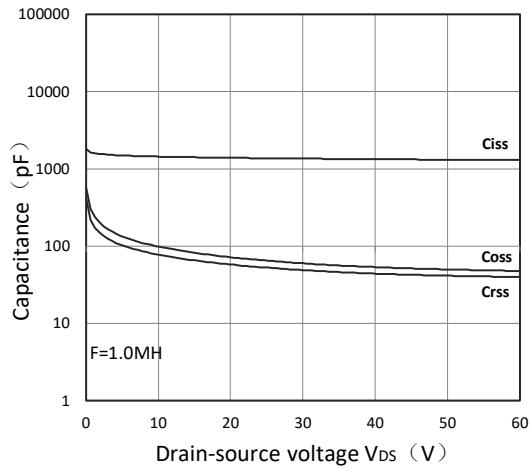


Figure 7. Capacitance Characteristics

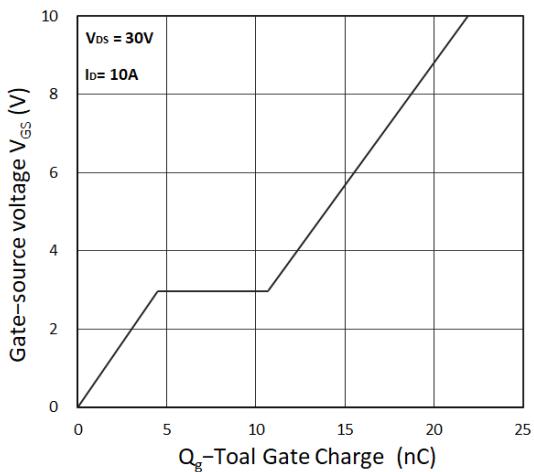


Figure 8. Gate Charge Characteristics

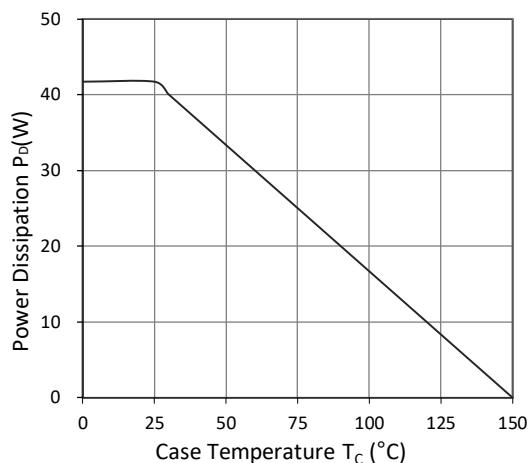


Figure 9. Power Dissipation

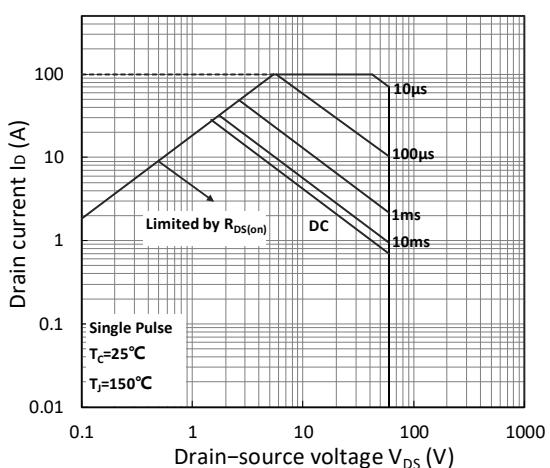


Figure10. Safe Operating Area

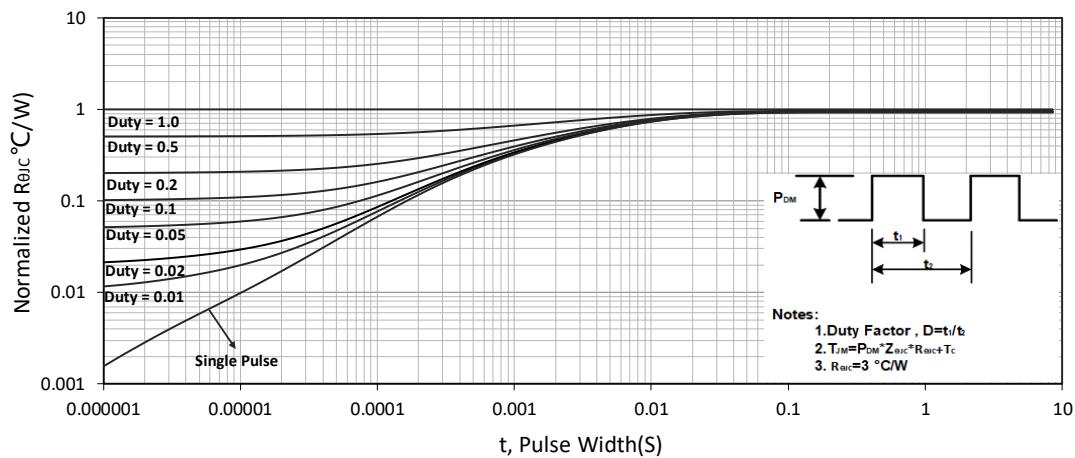


Figure 11. Normalized Maximum Transient Thermal Impedance